

Features

- 168 Pin JEDEC Standard, Unbuffered 8 Byte Dual In-line Memory Module
- 1Mx64, 1Mx72 Extended Data Out Page Mode DIMMs
- Performance:

		-60	-70
t _{RAC}	RAS Access Time	60ns	70ns
t _{CAC}	CAS Access Time	15ns	20ns
t _{AA}	Access Time From Address	30ns	35ns
t _{RC}	Cycle Time	104ns	124ns
t _{HPC}	EDO Mode Cycle Time	25ns	30ns

- All inputs and outputs are LVTTTL (3.3V) compatible
- Single 3.3V $\pm$ 0.3V Power Supply
- Au contacts
- Optimized for byte-write non-parity, or ECC

applications

- System Performance Benefits:
 - Non buffered for increased performance
 - Reduced noise (35 V_{SS}/V_{CC} pins)
 - Byte write, byte read accesses
 - Serial PDs
- Extended Data Out (EDO) Mode, Read-Modify-Write Cycles
- Refresh Modes: $\overline{\text{RAS}}$ -Only, CBR and Hidden Refresh
- 1024 refresh cycles distributed across 16ms
- 10/10 addressing (Row/Column)
- Card size: 5.25" x 1.0" x 0.354"
- DRAMS in SOJ Package

Description

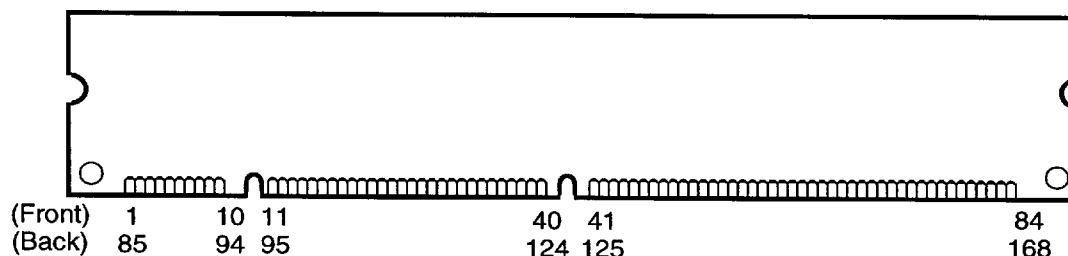
IBM11N1645B and IBM11N1735B are industry standard 168-pin 8-byte Dual In-line Memory Modules (DIMMs) which are organized as 1Mx64 and 1Mx72 high speed memory arrays designed with EDO DRAMs for non-parity or ECC applications. The DIMMs use 16 (x64) or 18 (x72) 1Mx4 EDO DRAMs in SOJ packages. The use of EDO DRAMs allows for a reduction in Page Mode Cycle time from 40ns (Fast Page) to 25ns for 60ns DRAM modules.

The DIMMs use serial presence detects implemented via a serial EEPROM using the two pin I²C protocol. This communication protocol uses Clock (SCL) and Data I/O (SDA) lines to synchronously

clock data between the master (system logic) and the slave EEPROM device (DIMM). The EEPROM device address pins (SA0-2) are brought out to the DIMM tabs to allow 8 unique DIMM/EEPROM addresses. The first 128 bytes are utilized by the DIMM manufacturer and the second 128 bytes of serial PD data are available to the customer.

All IBM 168-pin DIMMs provide a high performance, flexible 8-byte interface in a 5.25" long space-saving footprint. Related products include the buffered DIMMs (x64, x72 parity and x72 ECC Optimized) for applications which can benefit from the on-card buffers.

Card Outline



Pin Description

RAS0, RAS2	Row Address Strobe	V _{CC}	Power (3.3V)
CAS0 - CAS7	Column Address Strobe	V _{SS}	Ground
WE0, WE2	Read/write Input	NC	No Connect
OE0, OE2	Output Enable	DU	Don't Use
A0 - A9	Address Inputs	SCL	Serial Presence Detect Clock Input
DQx	Data Input/Output	SDA	Serial Presence Detect Data Input
CBx	Check Bit Data Input/Output	SA0-2	Serial Presence Detect Address Inputs

Pinout

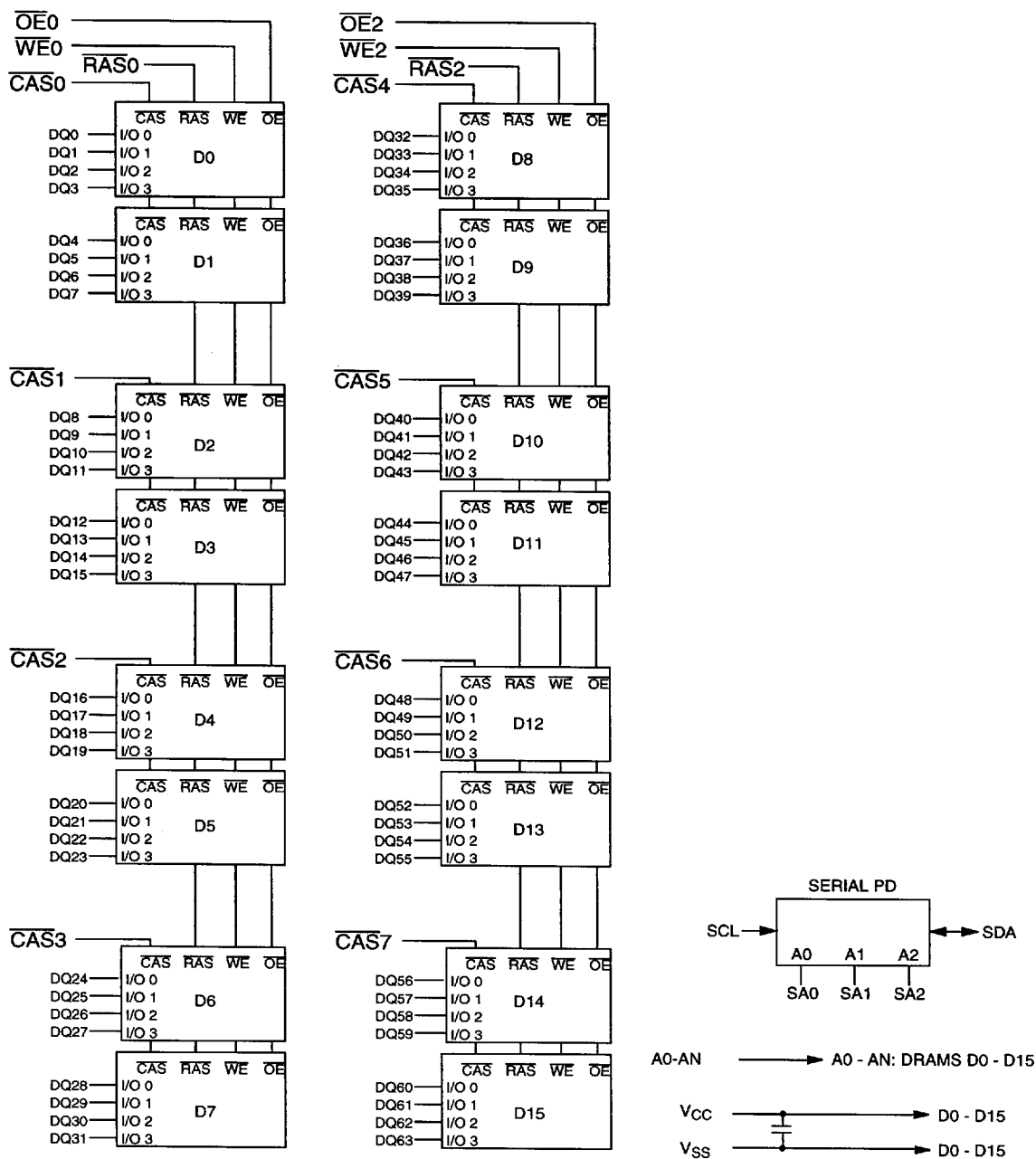
Pin#	Front Side	Pin#	Back Side	Pin#	Front Side	Pin#	Back Side	Pin#	Front Side	Pin#	Back Side	Pin#	Front Side	Pin#	Back Side
1	V _{SS}	85	V _{SS}	22	CB1	106	CB5	43	V _{SS}	127	V _{SS}	64	V _{SS}	148	V _{SS}
2	DQ0	86	DQ32	23	V _{SS}	107	V _{SS}	44	OE2	128	DU	65	DQ21	149	DQ53
3	DQ1	87	DQ33	24	NC	108	NC	45	RAS2	129	NC	66	DQ22	150	DQ54
4	DQ2	88	DQ34	25	NC	109	NC	46	CAS2	130	CAS6	67	DQ23	151	DQ55
5	DQ3	89	DQ35	26	V _{CC}	110	V _{CC}	47	CAS3	131	CAS7	68	V _{SS}	152	V _{SS}
6	V _{CC}	90	V _{CC}	27	WE0	111	DU	48	WE2	132	DU	69	DQ24	153	DQ56
7	DQ4	91	DQ36	28	CAS0	112	CAS4	49	V _{CC}	133	V _{CC}	70	DQ25	154	DQ57
8	DQ5	92	DQ37	29	CAS1	113	CAS5	50	NC	134	NC	71	DQ26	155	DQ58
9	DQ6	93	DQ38	30	RAS0	114	NC	51	NC	135	NC	72	DQ27	156	DQ59
10	DQ7	94	DQ39	31	OE0	115	DU	52	CB2	136	CB6	73	V _{CC}	157	V _{CC}
11	DQ8	95	DQ40	32	V _{SS}	116	V _{SS}	53	CB3	137	CB7	74	DQ28	158	DQ60
12	V _{SS}	96	V _{SS}	33	A0	117	A1	54	V _{SS}	138	V _{SS}	75	DQ29	159	DQ61
13	DQ9	97	DQ41	34	A2	118	A3	55	DQ16	139	DQ48	76	DQ30	160	DQ62
14	DQ10	98	DQ42	35	A4	119	A5	56	DQ17	140	DQ49	77	DQ31	161	DQ63
15	DQ11	99	DQ43	36	A6	120	A7	57	DQ18	141	DQ50	78	V _{SS}	162	V _{SS}
16	DQ12	100	DQ44	37	A8	121	A9	58	DQ19	142	DQ51	79	NC	163	NC
17	DQ13	101	DQ45	38	NC	122	NC	59	V _{CC}	143	V _{CC}	80	NC	164	NC
18	V _{CC}	102	V _{CC}	39	NC	123	NC	60	DQ20	144	DQ52	81	NC	165	SA0
19	DQ14	103	DQ46	40	V _{CC}	124	V _{CC}	61	NC	145	NC	82	SDA	166	SA1
20	DQ15	104	DQ47	41	V _{CC}	125	DU	62	DU	146	DU	83	SCL	167	SA2
21	CB0	105	CB4	42	DU	126	DU	63	NC	147	NC	84	V _{CC}	168	V _{CC}

Note: All pin assignments are consistent for all 8 Byte unbuffered versions.

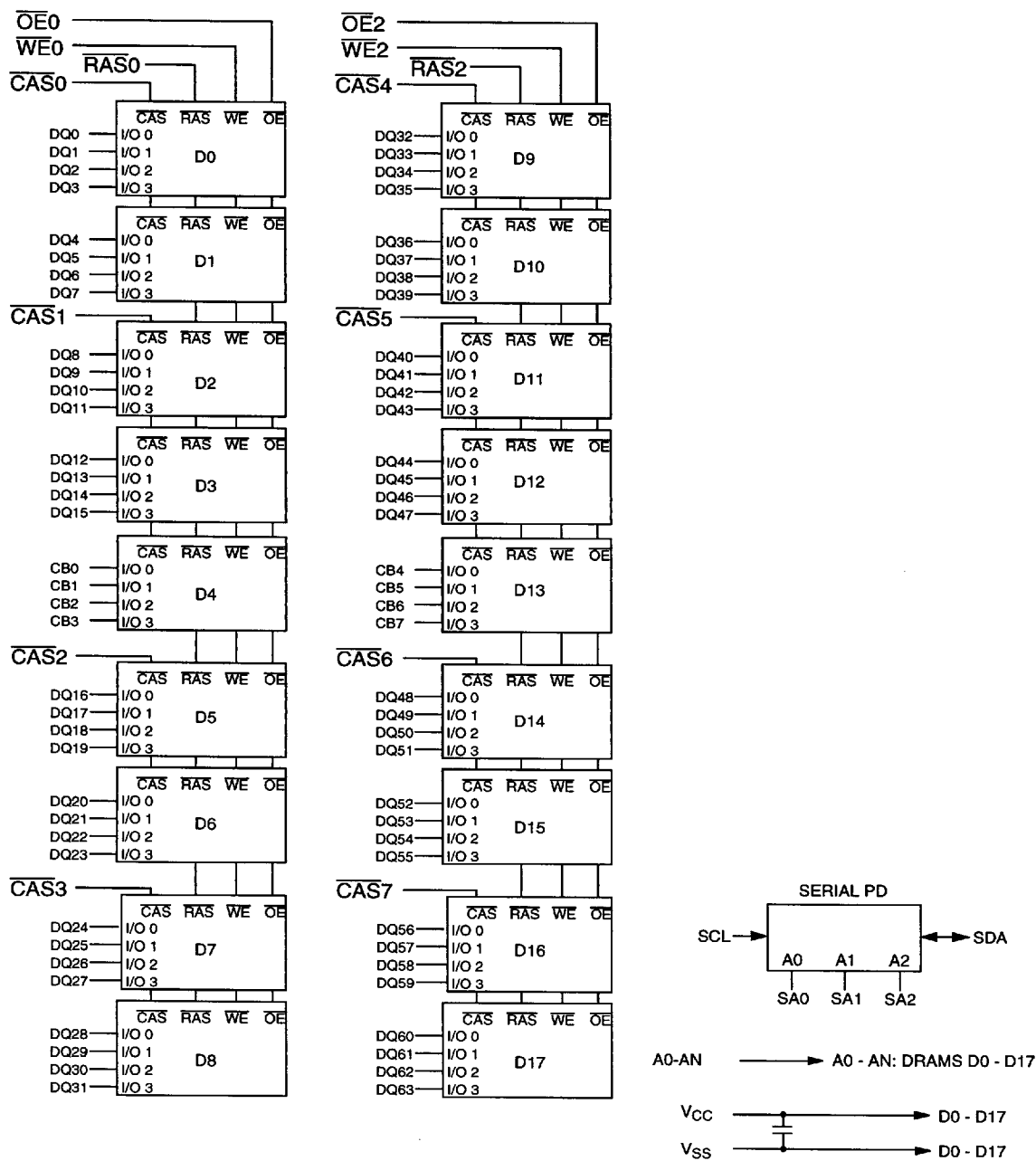
Ordering Information

Part Number	Organization	Speed	Addr.	Leads	Dimension	Power
IBM11N1645BB-60J	1Mx64	60ns	10/10	Au	5.25"x1.0"x 0.354"	3.3V
IBM11N1645BB-70J		70ns				
IBM11N1735BB-60J	1Mx72	60ns				
IBM11N1735BB-70J		70ns				

x64 DIMM Block Diagram (1 Bank, x4 DRAMs)



x72 ECC DIMM Block Diagram (1 Bank, x4 DRAMs)



Truth Table

Function		$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	WE	$\overline{\text{OE}}$	Row Address	Column Address	DQx
Standby		H	H→X	X	X	X	X	High Impedance
Read		L	L	H	L	Row	Col	Valid Data Out
Early-Write		L	L	L	X	Row	Col	Valid Data In
Late-Write		L	L	H→L	H	Row	Col	Valid Data In
RMW		L	L	H→L	L→H	Row	Col	Valid Data In/Out
EDO Page Mode - Read 1st Cycle		L	H→L	H	L	Row	Col	Valid Data Out
Subsequent Cycles		L	H→L	H	L	N/A	Col	Valid Data Out
EDO Page Mode - Write 1st Cycle		L	H→L	L	X	Row	Col	Valid Data In
Subsequent Cycles		L	H→L	L	X	N/A	Col	Valid Data In
EDO Page Mode - RMW 1st Cycle		L	H→L	H→L	L→H	Row	Col	Valid Data In/Out
Subsequent Cycles		L	H→L	H→L	L→H	N/A	Col	Valid Data In/Out
RAS-Only Refresh		L	H	X	X	Row	N/A	High Impedance
CAS-Before-RAS Refresh		H→L	L	H	X	X	X	High Impedance
Hidden Refresh	Read	L→H→L	L	H	L	Row	Col	Data Out
	Write	L→H→L	L	H	X	Row	Col	Data In
Self Refresh		H→L	L	H	X	X	X	High Impedance

Serial Presence Detect

			SPD Entry Value	SPD Entry								Hex
				Binary								
Byte #	Description			Bit 7	Bit 6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0	
0	Number of SPD Bytes		128	1	0	0	0	0	0	0	0	80
1	Total # Bytes in Serial PD		256	0	0	0	0	1	0	0	0	08
2	Memory Type		EDO	0	0	0	0	0	0	1	0	02
3	# of Row Addresses		10	0	0	0	0	1	0	1	0	0A
4	# of Column Addresses		10	0	0	0	0	1	0	1	0	0A
5	# of DIMM Banks		1	0	0	0	0	0	0	0	1	01
6	Module Data Width		x64	0	1	0	0	0	0	0	0	40
			x72	0	1	0	0	1	0	0	0	48
7	Module Data Width (Cont.)		0	0	0	0	0	0	0	0	0	00
8	Module Interface Levels		LVTTL	0	0	0	0	0	0	0	1	01
9	RAS Access	60ns	60	0	0	1	1	1	1	0	0	3C
		70ns	70	0	1	0	0	0	1	1	0	46
10	CAS Access	15ns	15	0	0	0	0	1	1	1	1	0F
		20ns	20	0	0	0	1	0	1	0	0	14
11	Dimm Config(Error Det/Corr.)	x64	None	0	0	0	0	0	0	0	0	00
		x72	ECC	0	0	0	0	0	0	1	0	02
12	Refresh Rate/Type		Normal 15.6 μs	0	0	0	0	0	0	0	0	00

Absolute Maximum Ratings

Symbol	Parameter	Rating (3.3V)	Units	Notes
V_{CC}	Power Supply Voltage	-0.5 to +4.6	V	1
V_{IN}	Input Voltage	-0.5 to min ($V_{CC} + 0.5$, 4.6)	V	1
$V_{IN/OUT}$ (SPD)	Input Voltage (Serial PD Device)	-0.3 to +6.5	V	1
V_{OUT}	Output Voltage	-0.5 to min ($V_{CC} + 0.5$, 4.6)	V	1
T_{OPR}	Operating Temperature	0 to +70	°C	1
T_{STG}	Storage Temperature	-55 to +125	°C	1
P_D	Power Dissipation	x64	W	1
		x72		
I_{OUT}	Short Circuit Output Current	50	mA	1

1. Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated is not implied. Exposure to absolute maximum rating condition for extended periods may affect reliability.

Recommended DC Operating Conditions ($T_A = 0$ to 70°C)

Symbol	Parameter	3.3V			Units	Notes
		Min	Typ	Max		
V_{CC}	Supply Voltage	3.0	3.3	3.6	V	1
V_{IH}	Input High Voltage	2.0	—	$V_{CC} + 0.3$	V	1, 2
V_{IL}	Input Low Voltage	-0.3	—	0.8	V	1, 2

1. All voltages referenced to V_{SS} .
 2. V_{IH} may overshoot to $V_{CC} + 1.2\text{V}$ for pulse widths of $\leq 4.0\text{ns}$ (or $V_{CC} + 1.0\text{V}$ for $\leq 8.0\text{ns}$). Additionally, V_{IL} may undershoot to -2.0V for pulse widths $\leq 4.0\text{ns}$ (or -1.0V for $\leq 8.0\text{ns}$). Pulse widths measured at 50% points with amplitude measured peak to DC reference.

Capacitance ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 3.3\text{V} \pm 0.3\text{V}$)

Symbol	Parameter	Max		Units
		x64	x72	
C_{I1}	Input Capacitance (A0-A11)	90	100	pF
C_{I2}	Input Capacitance (RAS, WE, OE)	70	75	pF
C_{I3}	Input Capacitance (CAS)	20	25	pF
C_{I4}	Input Capacitance (SCL, SA0-3)	8	8	pF
C_{IO1}	Input/Output Capacitance (DQx, CBx)	11	11	pF
C_{IO2}	Input/Output Capacitance (SDA)	10	10	pF

DC Electrical Characteristics (T_A = 0 to +70°C, V_{CC} = 3.3V ± 0.3V)

Symbol	Parameter		x64		x72		Units	Notes
			Min.	Max.	Min.	Max.		
I _{CC1}	Operating Current Average Power Supply Operating Current (R _{AS} , C _{AS} , Address Cycling: t _{RC} = t _{RC} min.)	-60	—	1520	—	1710	mA	1, 2, 3
		-70	—	1280	—	1440		
I _{CC2}	Standby Current (TTL) Power Supply Standby Current (R _{AS} = C _{AS} = V _{IH})		—	32	—	36	mA	
I _{CC3}	R _{AS} Only Refresh Current Average Power Supply Current, R _{AS} Only Mode (R _{AS} Cycling, C _{AS} = V _{IH} : t _{RC} = t _{RC} min)	-60	—	1520	—	1710	mA	1, 3
		-70	—	1280	—	1440		
I _{CC4}	EDO Page Mode Current Average Power Supply Current, EDO Page Mode (R _{AS} = V _{IL} , C _{AS} , Address Cycling: t _{HPC} = t _{HPC} min)	-60	—	1040	—	1170	mA	1, 2, 3
		-70	—	1040	—	1170		
I _{CC5}	Standby Current (CMOS) Power Supply Standby Current (R _{AS} = C _{AS} = V _{CC} - 0.2V)		—	16	—	18	mA	
I _{CC6}	C _{AS} Before R _{AS} Refresh Current Average Power Supply Current, C _{AS} Before R _{AS} Mode (R _{AS} , C _{AS} , Cycling: t _{RC} = t _{RC} min)	-60	—	1520	—	1710	mA	1, 3
		-70	—	1280	—	1440		
I _{I(L)}	Input Leakage Current Input Leakage Current, any input (0.0 ≤ V _{IN} ≤ (V _{CC} + 0.3V)), All Other Pins Not Under Test = 0V	R _{AS} , WE, OE	-80	+80	-90	+90	μA	
		C _{AS}	-20	+20	-30	+30		
		Address	-160	+160	-180	+180		
I _{O(L)}	Output Leakage Current (D _{OUT} is disabled, 0.0 ≤ V _{OUT} ≤ V _{CC})		-10	+10	-10	+10	μA	
V _{OH}	Output Level (TTL) Output "H" Level Voltage (I _{OUT} = -2mA)		2.4	V _{CC}	2.4	V _{CC}	V	
V _{OL}	Output Level (TTL) Output "L" Level Voltage (I _{OUT} = +2mA)		0.0	0.4	0.0	0.4	V	
1. I _{CC1} , I _{CC3} , I _{CC4} and I _{CC6} depend on cycle rate. 2. I _{CC1} and I _{CC4} depend on output loading. Specified values are obtained with the output open. 3. Address can be changed once or less while R _{AS} = V _{IL} . In the case of I _{CC4} , it can be changed once or less when C _{AS} = V _{IH} .								

AC Characteristics ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 3.3\text{V} \pm 0.3\text{V}$)

1. V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Transition times are measured between V_{IH} and V_{IL} .
2. An initial pause of $200\mu\text{s}$ is required after power-up followed by 8 $\overline{\text{RAS}}$ only refresh cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycles instead of 8 $\overline{\text{RAS}}$ only refresh cycles is required..
3. AC measurements assume $t_T = 2\text{ns}$.

Read, Write, Read-Modify-Write and Refresh Cycles (Common Parameters)

Symbol	Parameter	-60		-70		Unit	Notes
		Min	Max	Min	Max		
t_{RC}	Random Read or Write Cycle Time	104	—	124	—	ns	
t_{RP}	$\overline{\text{RAS}}$ Precharge Time	40	—	50	—	ns	
t_{CP}	$\overline{\text{CAS}}$ Precharge Time	10	—	10	—	ns	
t_{RAS}	$\overline{\text{RAS}}$ Pulse Width	60	10K	70	10K	ns	
t_{CAS}	$\overline{\text{CAS}}$ Pulse Width	10	10K	12	10K	ns	
t_{ASR}	Row Address Setup Time	0	—	0	—	ns	
t_{RAH}	Row Address Hold Time	10	—	10	—	ns	
t_{ASC}	Column Address Setup Time	0	—	0	—	ns	
t_{CAH}	Column Address Hold Time	10	—	10	—	ns	
t_{RCD}	$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay Time	14	45	14	50	ns	1
t_{RAD}	$\overline{\text{RAS}}$ to Column Address Delay Time	12	30	12	35	ns	2
t_{RSH}	$\overline{\text{RAS}}$ Hold Time	10	—	12	—	ns	
t_{CSH}	$\overline{\text{CAS}}$ Hold Time	50	—	55	—	ns	
t_{CRP}	$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time	5	—	5	—	ns	
t_{ODD}	$\overline{\text{OE}}$ to D_{IN} Delay Time	15	—	15	—	ns	3
t_{DZO}	$\overline{\text{OE}}$ Delay Time from D_{IN}	0	—	0	—	ns	4
t_{DZC}	$\overline{\text{CAS}}$ Delay Time from D_{IN}	0	—	0	—	ns	4
t_T	Transition Time (Rise and Fall)	2	30	2	30	ns	

1. Operation within the $t_{RCD}(\text{max})$ limit ensures that $t_{RAC}(\text{max})$ can be met. The $t_{RCD}(\text{max})$ is specified as a reference point only: If t_{RCD} is greater than the specified $t_{RCD}(\text{max})$ limit, then access time is controlled by t_{CAC} .

2. Operation within the $t_{RAD}(\text{max})$ limit ensures that $t_{RAC}(\text{max})$ can be met. The $t_{RAD}(\text{max})$ is specified as a reference point only: If t_{RAD} is greater than the specified $t_{RAD}(\text{max})$ limit, then access time is controlled by t_{AA} .

3. Either t_{CDD} or t_{ODD} must be satisfied.

4. Either t_{DZC} or t_{DZO} must be satisfied.

Write Cycle

Symbol	Parameter	-60		-70		Unit	Notes
		Min	Max	Min	Max		
t_{WCS}	Write Command Set Up Time	0	—	0	—	ns	1
t_{WCH}	Write Command Hold Time	10	—	12	—	ns	
t_{WP}	Write Command Pulse Width	10	—	12	—	ns	
t_{RWL}	Write Command to $\overline{RAS}$ Lead Time	10	—	12	—	ns	
t_{CWL}	Write Command to $\overline{CAS}$ Lead Time	10	—	12	—	ns	
t_{DS}	D_{IN} Setup Time	0	—	0	—	ns	2
t_{DH}	D_{IN} Hold Time	10	—	12	—	ns	2
1. t_{WCS}, t_{RWD}, t_{CWD}, and t_{AWD} are not restrictive parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}(\text{min.})$, the entire cycle is an early write cycle and the data pin will remain open circuit (high impedance) through the entire cycle; If $t_{RWD} \geq t_{RWD}(\text{min.})$, $t_{CWD} \geq t_{CWD}(\text{min.})$ and $t_{AWD} \geq t_{AWD}(\text{min.})$, the cycle is a Read-Modify-Write cycle and the data will contain read from the selected cell: If neither of the above sets of conditions are met, the condition of the data (at access time) is indeterminate. 2. Data-in set-up and hold is measured from the latter of the two timings, $\overline{CAS}$ or $\overline{WE}$.							



Read Cycle

Symbol	Parameter	-60		-70		Unit	Notes
		Min	Max	Min	Max		
t_{RAC}	Access Time from $\overline{RAS}$	—	60	—	70	ns	1, 2
t_{CAC}	Access Time from $\overline{CAS}$	—	15	—	20	ns	1, 2
t_{AA}	Access Time from Address	—	30	—	35	ns	1, 2
t_{OEA}	Access Time from $\overline{OE}$	—	15	—	20	ns	1, 2
t_{RCS}	Read Command Setup Time	0	—	0	—	ns	
t_{RCH}	Read Command Hold Time to $\overline{CAS}$	0	—	0	—	ns	3
t_{RRH}	Read Command Hold Time to $\overline{RAS}$	0	—	0	—	ns	3
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	30	—	35	—	ns	
t_{CLZ}	$\overline{CAS}$ to Output in Low-Z	0	—	0	—	ns	
t_{OES}	$\overline{OE}$ setup time prior to $\overline{CAS}$	5	—	5	—	ns	
t_{ORD}	$\overline{OE}$ setup time prior to $\overline{RAS}$ (Hidden Refresh)	0	—	0	—	ns	
t_{CDD}	$\overline{CAS}$ to D_{IN} Delay Time	15	—	15	—	ns	5
t_{OEZ}	Output Buffer Turn-off Delay from $\overline{OE}$	—	15	—	15	ns	4
t_{OFF}	Output Buffer Turn-off Delay	—	15	—	15	ns	4, 6

1. Measured with the specified current load and 100pF.
2. Access time is determined by the latter of t_{RAC} , t_{CAC} , t_{CPA} , t_{AA} , t_{OEA} .
3. Either t_{RCH} or t_{RRH} must be satisfied.
4. t_{OFF} (max) and t_{OEZ} (max) define the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
5. Either t_{CDD} or t_{ODD} must be satisfied.
6. t_{OFF} is referenced from the rising edge of $\overline{RAS}$ or $\overline{CAS}$, whichever is last.

Read-Modify-Write Cycle

Symbol	Parameter	-60		-70		Unit	Notes
		Min	Max	Min	Max		
t_{RWC}	Read-Modify-Write Cycle Time	135	—	162	—	ns	
t_{RWD}	$\overline{RAS}$ to $\overline{WE}$ Delay Time	79	—	94	—	ns	1
t_{CWD}	$\overline{CAS}$ to $\overline{WE}$ Delay Time	34	—	44	—	ns	1
t_{AWD}	Column Address to $\overline{WE}$ Delay Time	49	—	59	—	ns	1
t_{OEh}	$\overline{OE}$ Command Hold Time	10	—	12	—	ns	

1. t_{WCS} , t_{RWD} , t_{CWD} , and t_{AWD} are not restrictive parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}(\text{min.})$, the entire cycle is an early write cycle and the data pin will remain open circuit (high impedance) through the entire cycle; If $t_{RWD} \geq t_{RWD}(\text{min.})$, $t_{CWD} \geq t_{CWD}(\text{min.})$ and $t_{AWD} \geq t_{AWD}(\text{min.})$, the cycle is a Read-Modify-Write cycle and the data will contain read from the selected cell; If neither of the above sets of conditions are met, the condition of the data (at access time) is indeterminate.

EDO Mode Cycle

Symbol	Parameter	-60		-70		Units	Notes
		Min.	Max.	Min.	Max.		
t_{HCAS}	$\overline{CAS}$ Pulse Width (EDO Page Mode)	10	10K	12	10K	ns	
t_{HPC}	EDO Page Mode Cycle Time (Read/Write)	25	—	30	—	ns	
t_{HPRWC}	EDO Page Mode Read Modify Write Cycle Time	60	—	72	—	ns	
t_{DOH}	Data-out Hold Time from $\overline{CAS}$	5	—	5	—	ns	
t_{WHZ}	Output buffer Turn-Off Delay from $\overline{WE}$	0	10	0	15	ns	
t_{WPZ}	$\overline{WE}$ Pulse Width to Output Disable at $\overline{CAS}$ High	10	—	10	—	ns	
t_{CPRH}	$\overline{RAS}$ Hold Time from $\overline{CAS}$ Precharge	35	—	40	—	ns	
t_{CPA}	Access Time from $\overline{CAS}$ Precharge	—	35	—	40	ns	1
t_{RASP}	EDO Page Mode $\overline{RAS}$ Pulse Width	60	100K	70	100K	ns	
t_{OEP}	$\overline{OE}$ High Pulse Width	10	—	10	—	ns	
t_{OEHC}	$\overline{OE}$ High Hold Time from $\overline{CAS}$ High	10	—	10	—	ns	

1. Measured with the specified current load and 100pF at $V_{OL} = 0.8V$ and $V_{OH} = 2.0V$.

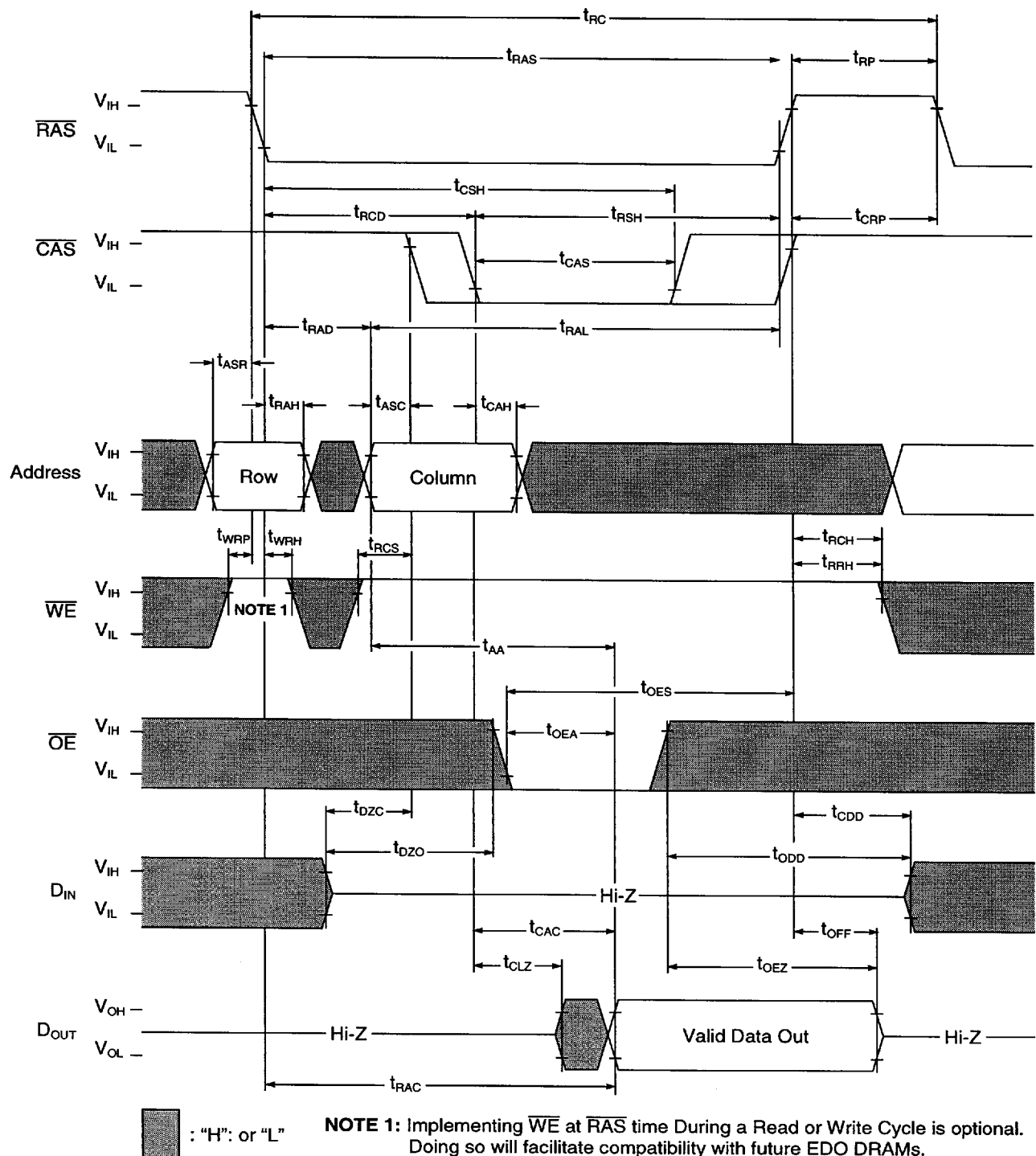
Refresh Cycle

Symbol	Parameter	-60		-70		Unit	Notes
		Min	Max	Min	Max		
t_{CHR}	CAS Hold Time (CAS before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{CSR}	CAS Setup Time (CAS before $\overline{RAS}$ Refresh Cycle)	5	—	5	—	ns	
t_{WRP}	WE Setup Time (CAS before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{WRH}	WE Hold Time (CAS before $\overline{RAS}$ Refresh Cycle)	10	—	10	—	ns	
t_{RPC}	$\overline{RAS}$ Precharge to CAS Hold Time	5	—	5	—	ns	
t_{REF}	Refresh Period	—	16	—	16	ms	1
1. 1024 refreshes are required every 16ms							

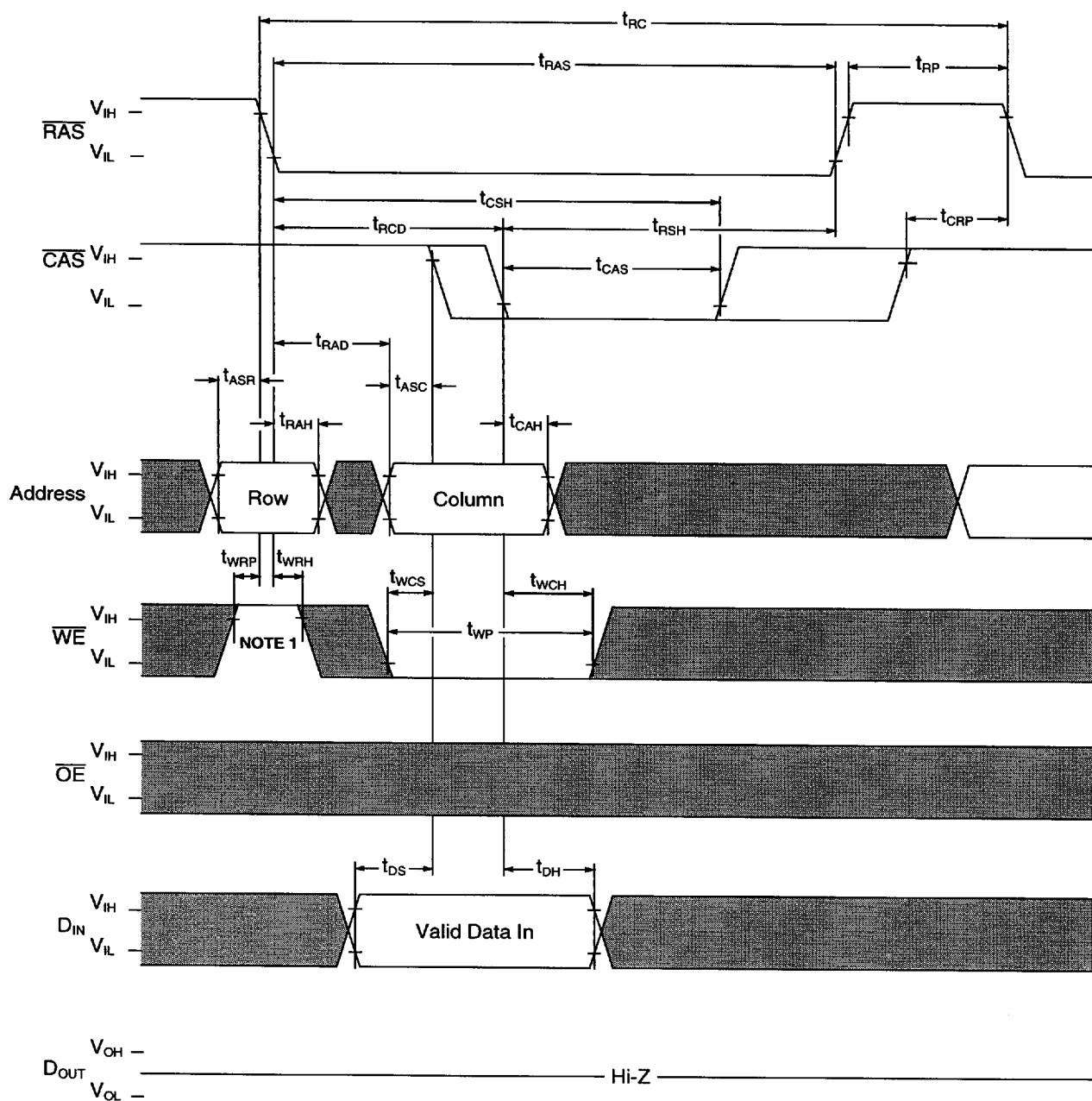
Presence Detect Read and Write Cycle

Symbol	Parameter	Min	Max	Unit	Notes
f_{SCL}	SCL Clock Frequency		100	KHZ	
T_I	Noise Suppression Time Constant at SCL, SDA Inputs		100	ns	
t_{AA}	SCL Low to SDA Data Out Valid	0.3	3.5	μ s	
t_{BUF}	Time the Bus Must Be Free before a New Transmission Can Start	4.7		μ s	
$t_{HD:STA}$	Start Condition Hold Time	4.0		μ s	
t_{LOW}	Clock Low Period	4.7		μ s	
t_{HIGH}	Clock High Period	4.0		μ s	
$t_{SU:STA}$	Start Condition Setup Time(for a Repeated Start Condition)	4.7		μ s	
$t_{HD:DAT}$	Data in Hold Time	0		μ s	
$t_{SU:DAT}$	Data in Setup Time	250		ns	
t_r	SDA and SCL Rise Time		1	μ s	
t_f	SDA and SCL Fall Time		300	ns	
$t_{SU:STO}$	Stop Condition Setup Time	4.7		μ s	
t_{DH}	Data Out Hold Time	300		ns	
t_{WR}	Write Cycle Time		15	ms	1
1. The write cycle time(t_{WR}) is the time from a valid stop condition of a write sequence to the end of the internal erase/program cycle. During the write cycle, the bus interface circuits are disabled, SDA is allowed to remain high per the bus-level pull-up resistor, and the device does not respond to its slave address.					

Read Cycle



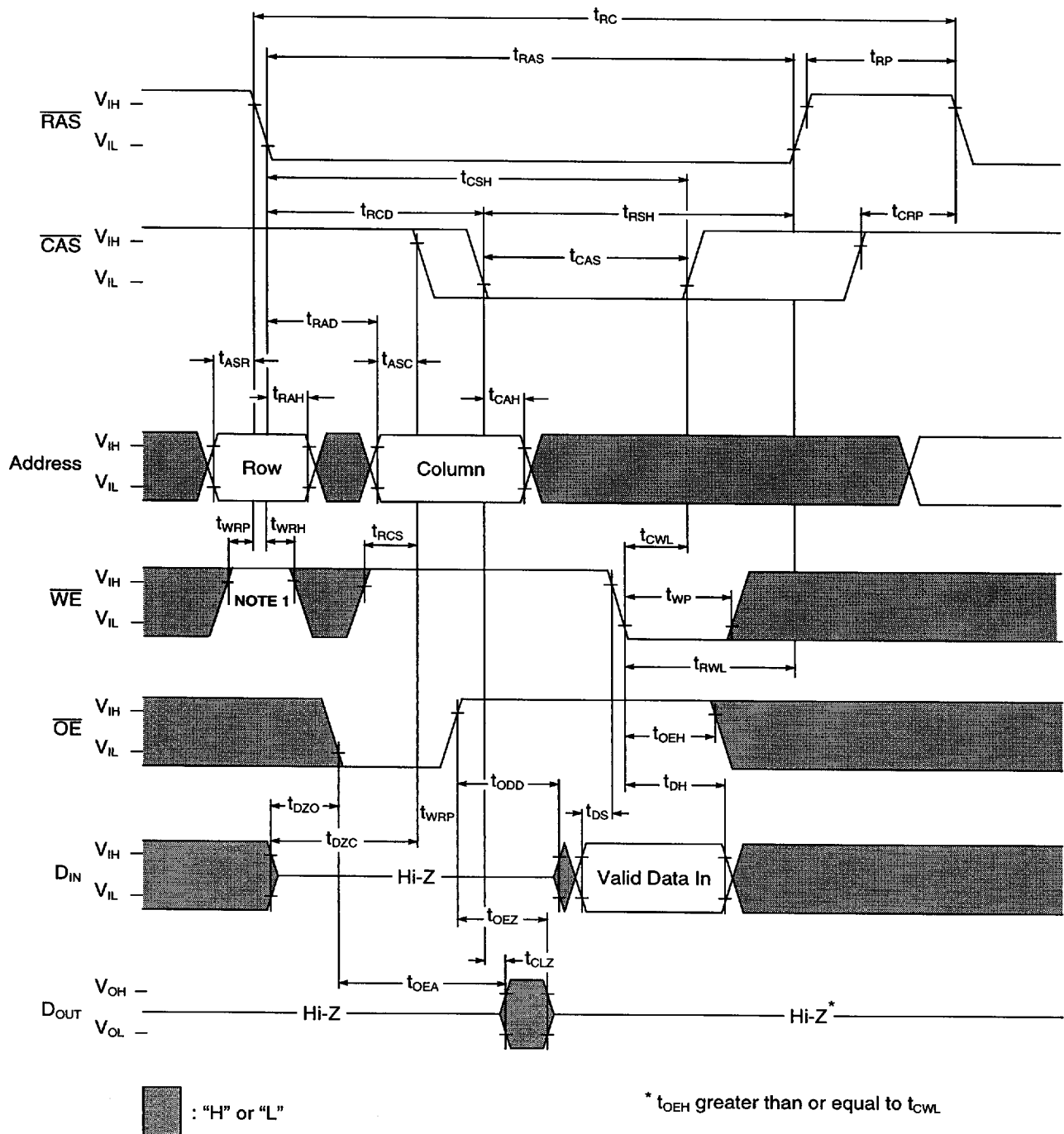
Write Cycle (Early Write)



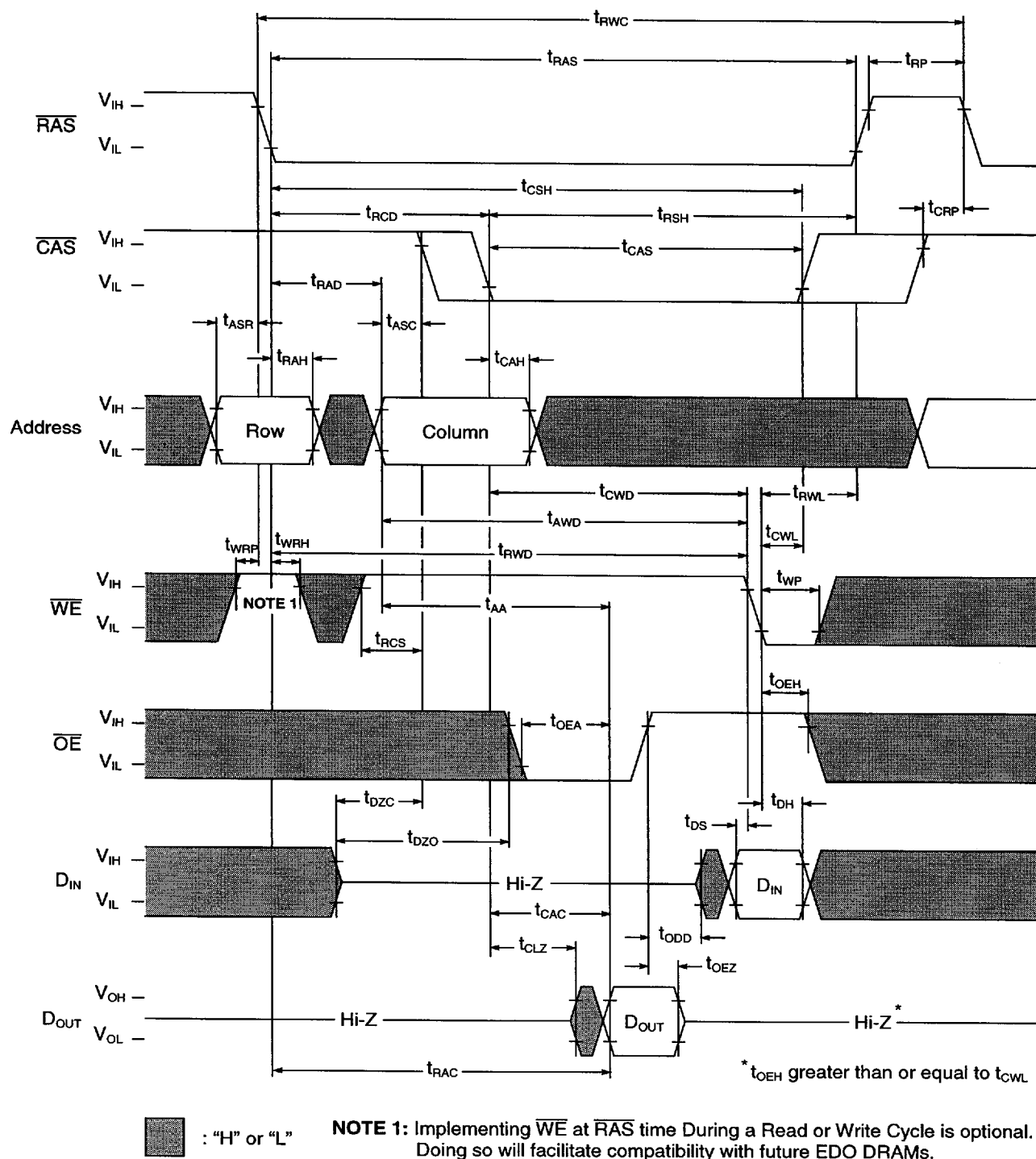
■ : "H" or "L"

NOTE 1: Implementing $\overline{WE}$ at $\overline{RAS}$ time During a Read or Write Cycle is optional. Doing so will facilitate compatibility with future EDO DRAMs.

Write Cycle (Late Write)



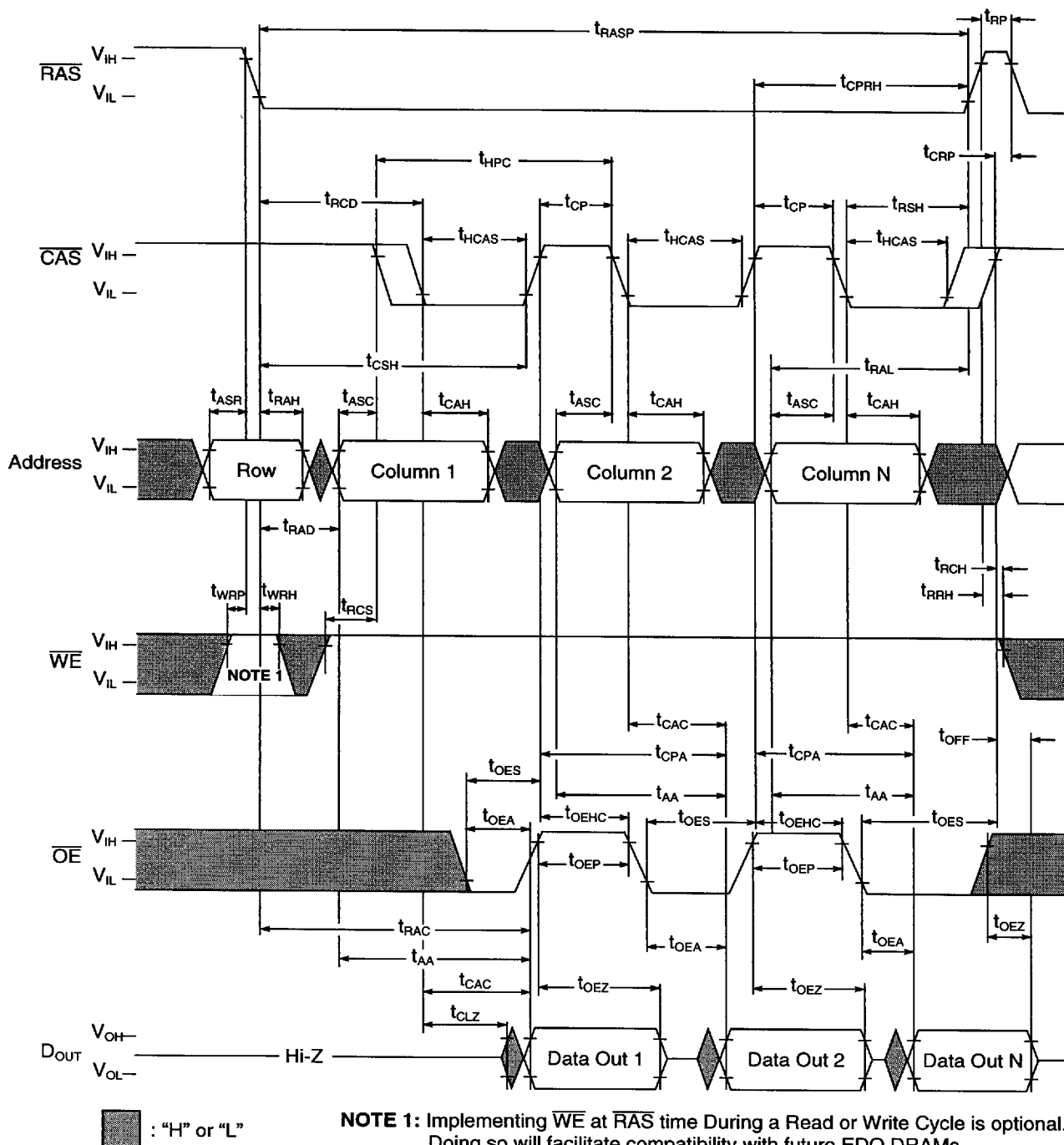
NOTE 1: Implementing $\overline{WE}$ at $\overline{RAS}$ time During a Read or Write Cycle is optional. Doing so will facilitate compatibility with future EDO DRAMs.



[illegible]

NOTE 1: Implementing $\overline{WE}$ at $\overline{RAS}$ time During a Read or Write Cycle is optional. Doing so will facilitate compatibility with future EDO DRAMs.

EDO Page Mode Read Cycle ($\overline{OE}$ Control)



Timing diagram for EDO DRAM showing RAS, CAS, Address, WE, OE, and DOUT signals with various timing parameters like t_{RAS} , t_{RCD} , t_{HPC} , t_{CP} , t_{RSH} , t_{RAL} , t_{ASC} , t_{CAH} , t_{RCH} , t_{RCS} , t_{WRP} , t_{WRH} , t_{RCS} , t_{OES} , t_{OEA} , t_{RAC} , t_{AA} , t_{CAC} , t_{CLZ} , t_{WHZ} , t_{OEZ} , t_{OFF} , t_{CPRH} , t_{CRP} , t_{ASR} , t_{RAH} , t_{ASC} , t_{CAH} , t_{AA} , t_{RCH} , t_{RCS} , t_{WRP} , t_{WRH} , t_{RCS} , t_{OES} , t_{OEA} , t_{RAC} , t_{AA} , t_{CAC} , t_{CLZ} , t_{WHZ} , t_{OEZ} , t_{OFF} , t_{CPRH} , t_{CRP} .

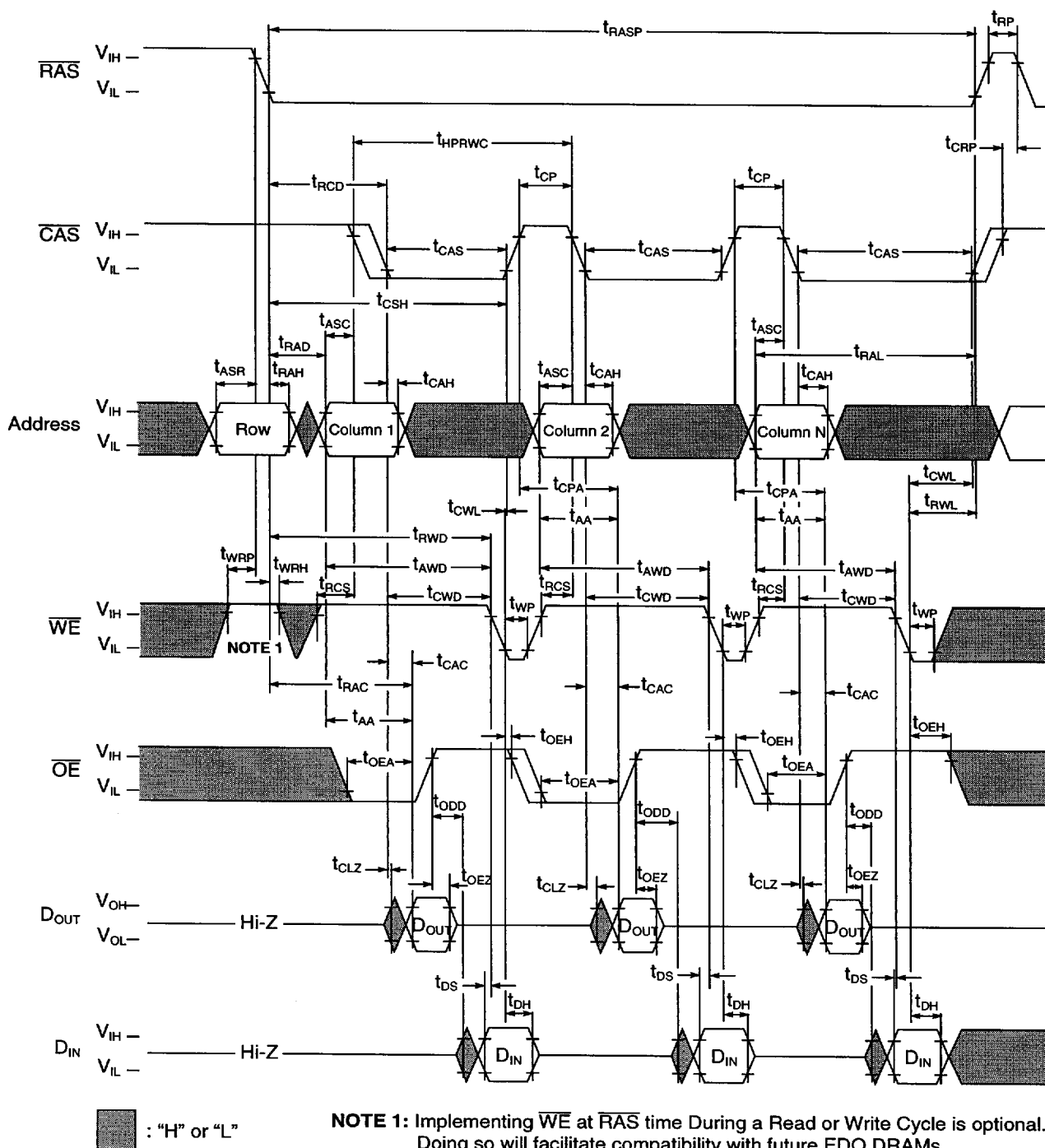
NOTE 1: Implementing WE at RAS time During a Read or Write Cycle is optional. Doing so will facilitate compatibility with future EDO DRAMs.

The diagram illustrates the timing relationships for a DRAM read cycle. It shows the signals RAS, CAS, Address, WE, OE, and DIN over time. The signals are labeled with their high (V_{IH}) and low (V_{IL}) levels. The timing parameters are defined as follows:

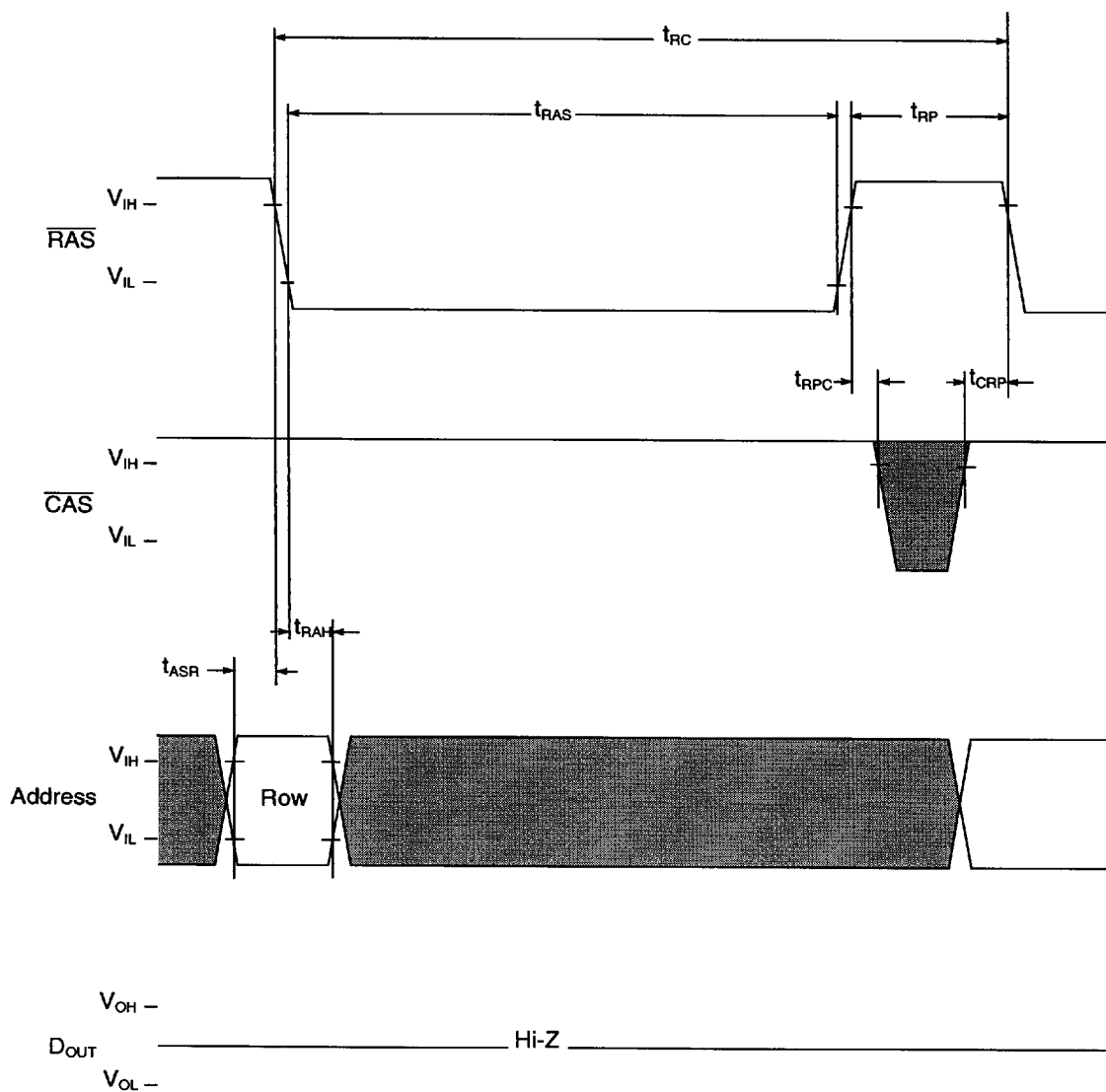
- t_{RASP}**: RAS pulse width.
- t_{RP}**: RAS precharge time.
- t_{RCD}**: Row to Column Delay.
- t_{HPC}**: High Precharge time.
- t_{CP}**: Column Precharge time.
- t_{RSH}**: Row Strobe time.
- t_{CRP}**: Column Refresh time.
- t_{RAD}**: Row Address Delay.
- t_{CSH}**: Column Strobe time.
- t_{ASC}**: Address to Strobe time.
- t_{CAH}**: Column Address time.
- t_{CWL}**: Column Write Latency.
- t_{RCS}**: Row to Column Strobe time.
- t_{WP}**: Write Pulse width.
- t_{OEH}**: Output Enable High time.
- t_{ODD}**: Output Data Delay.
- t_{DS}**: Data Strobe time.
- t_{DH}**: Data Hold time.

NOTE 1: Implementing $\overline{WE}$ at RAS time During a Read or Write Cycle is optional. Doing so will facilitate compatibility with future EDO DRAMs.

EDO Page Mode Read Modify Write Cycle



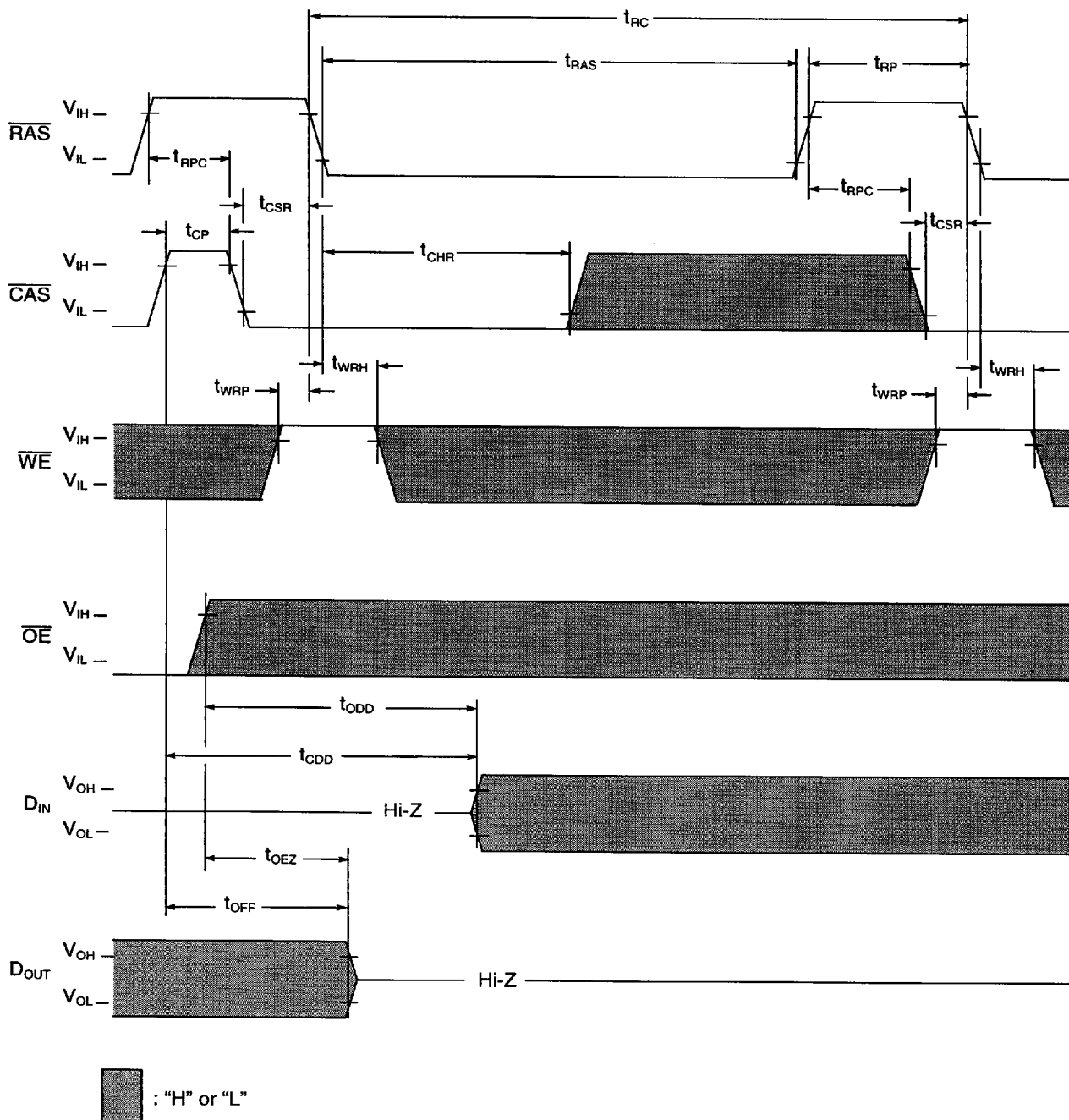
RAS Only Refresh Cycle



■ : "H" or "L"

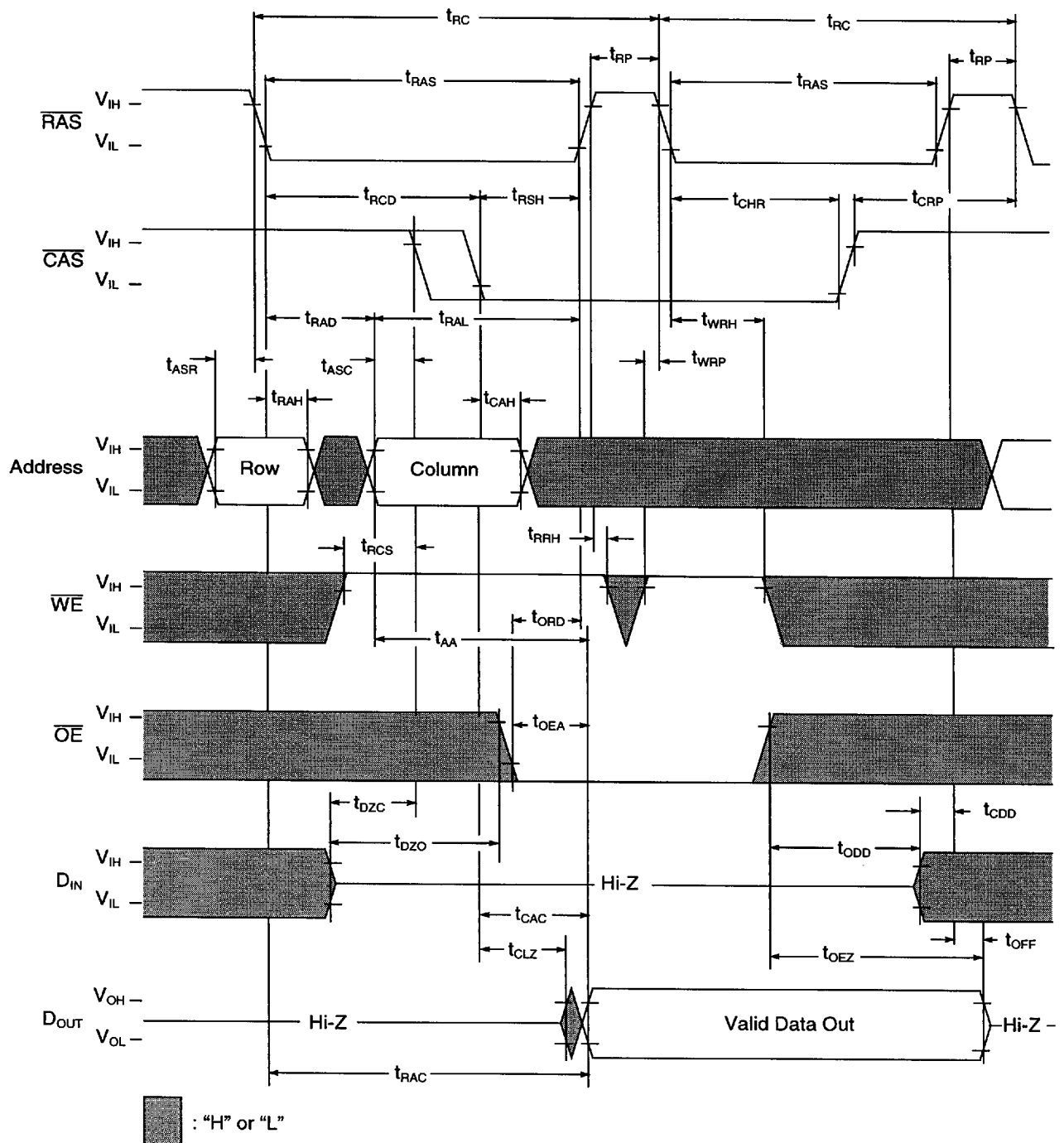
Note: $\overline{\text{WE}}$, $\overline{\text{OE}}$, D_{IN} are "H" or "L"

CAS Before RAS Refresh Cycle

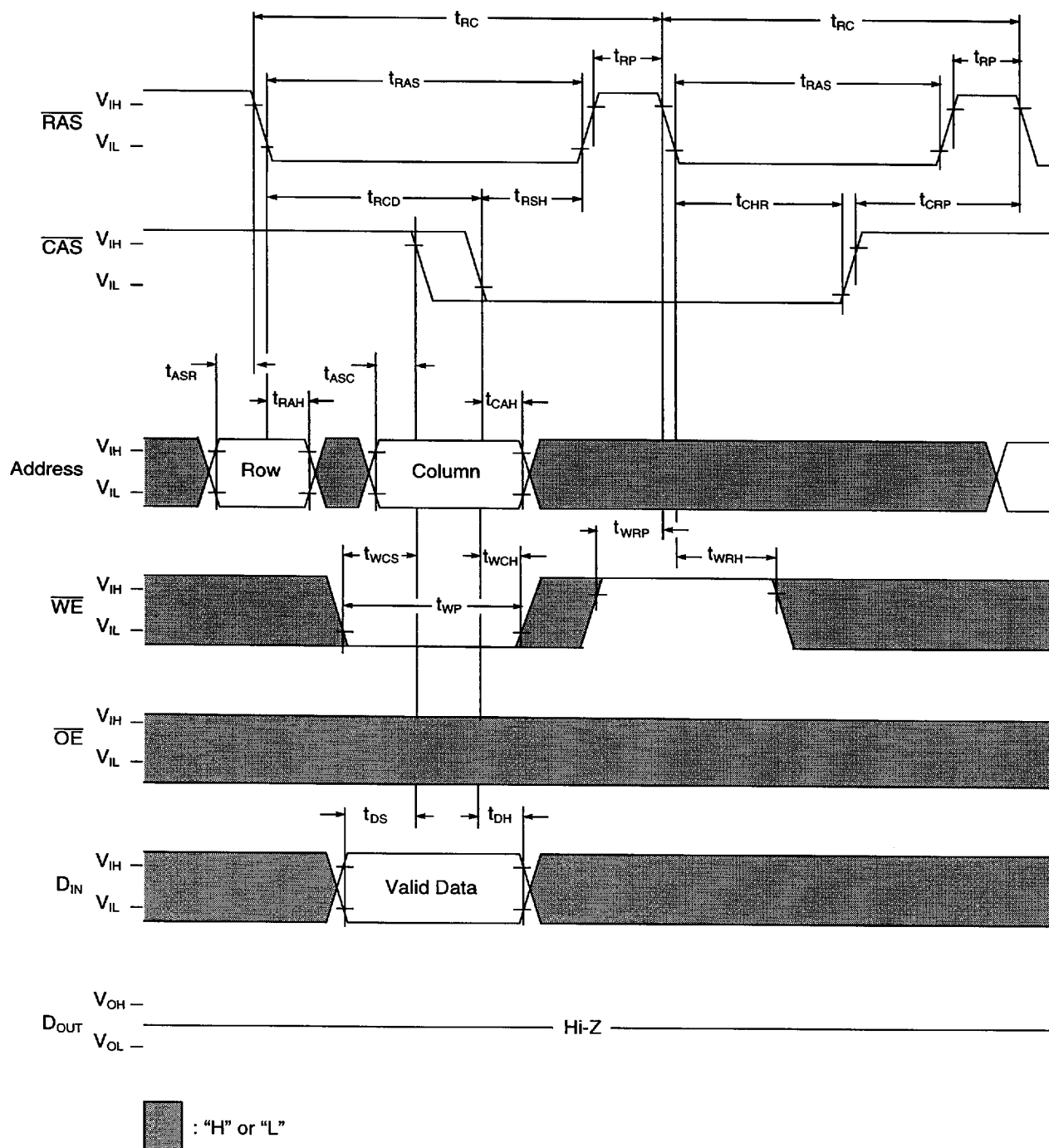


NOTE: Address is "H" or "L"

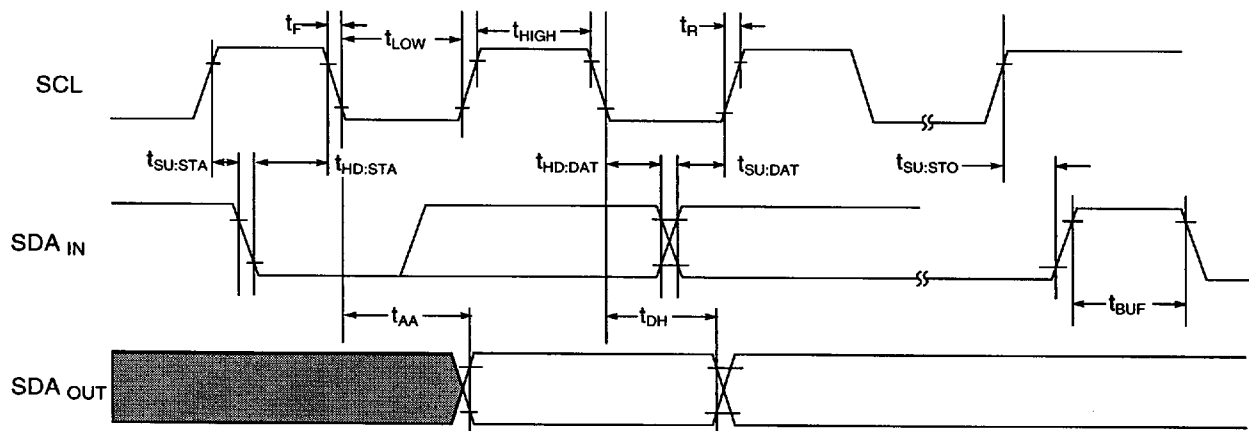
Hidden Refresh Cycle (Read)



Hidden Refresh Cycle (Write)



Presence Detect (EEPROM) Bus Timing



Presence Detect Operation

Clock and Data Conventions: Data states on the SDA line can change only during SCL low. SDA state changes during SCL HIGH are reserved for indicating start and stop conditions (Figure 1 & Figure 2).

Start Condition: All commands are preceded by the start condition, which is a HIGH to LOW transition of SDA when SCL is high. The serial PD device continuously monitors the SDA and SCL lines for the start condition and will not respond to any command until this condition has been met.

Stop Condition: All communications are terminated by a stop condition, which is a LOW to HIGH transition of SDA when SCL is HIGH. The stop condition is also used to place the serial PD device into standby power mode.

Acknowledge: Acknowledge is a software convention used to indicate successful data transfers. The transmitting device, either master or slave, will release the bus after transmitting eight bits. During the ninth clock cycle the receiver will pull the SDA line LOW to acknowledge that it received the eight bits of data (Figure 3).

The PD device will always respond with an acknowledge after recognition of a start condition and its slave address. If both the device and a write operation have been selected, The PD device, will respond with an acknowledge after the receipt of each subsequent eight bit word. In the read mode the PD device will transmit eight bits of data, release the SDA line and monitor the line for an

acknowledge. If an acknowledge is detected and

no stop condition is generated by the master, the slave will continue to transmit data. If an acknowledge is not detected, the slave will terminate further data transmissions and await the stop condition to return to standby power mode.

Figure 1. Data Window

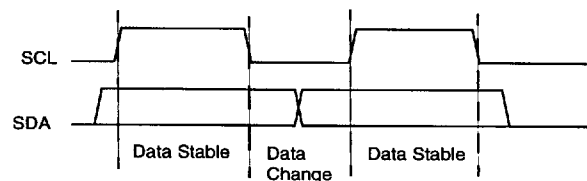


Figure 2. Definition of Start & Stop

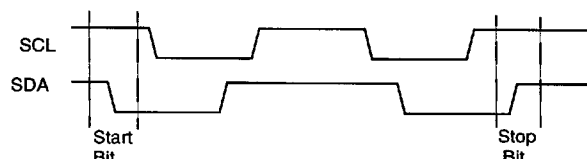
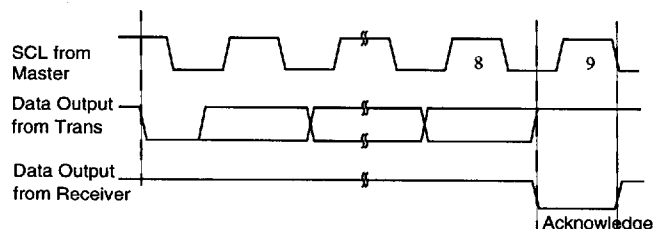


Figure 3. Acknowledge Response From Receiver





Revision Log

Rev	Contents of Modification
6/96	Initial Release.